

AFY/2863 JFW

Attorney Docket No.: CRDC-P0363

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**Patent**

In re Application of:

Inventor(s): Burnell G. West

Application No.: 10/056,287

Examiner:

Filed: 01/23/02

Art Unit:

For: CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT SYSTEM

Patent No.:

Issued Date:

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**POWER OF ATTORNEY BY ASSIGNEE OF ENTIRE INTEREST  
(REVOCATION OF PRIOR POWERS)**

As assignee of record of the entire interest of the above identified

☒ application,  
☐ patent,

**REVOCATION OF PRIOR POWERS OF ATTORNEY**

☒ I hereby revoke all previous powers of attorney given in the above-identified application/patent.

**NEW POWER OF ATTORNEY**

☒ I hereby appoint the practitioners associated with the customer Number: 45595

☒ Please change the correspondence address for the above-identified application to:

The address associated with Customer Number: : 45595

I am the:

☒ Assignee of record of the entire interest. *Statement under 37 CFR 3.73(b) is below.*

**CERTIFICATE UNDER 37 CFR 3.73(b)**

CREDENCE SYSTEMS CORPORATION., a California corporation, certifies that it is the assignee of the entire right, title and interest in the patent identified above by virtue of:

☐ An assignment from the inventor(s) of the patent application/patent identified above. The assignment was recorded in The United States Patent and Trademark Office at

Reel \_\_\_\_\_. Frame \_\_\_\_\_.

☒ Copies of assignments or other documents in the chain of title are attached.

The undersigned has reviewed all the documents in the chain of title of the patent application/patent identified above and, to the best of undersigned's knowledge and belief, title is in the assignee identified above.

**BEST AVAILABLE COPY**

The undersigned (whose title is supplied below) avers that the undersigned is empowered to sign this certificate on behalf of the assignee.

I hereby declare that all statements made herein of my own knowledge are true, and that all statements made on information and belief are believed to be true; and further, that these statements are made with the knowledge that willful false statements, and the like so made, are punishable by fine or imprisonment, or both, under Section 1001, Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

2/8/05  
Date

  
Signature

**Naomi Obinata, Assistant General Counsel**  
Typed or Printed Name

**Assistant General Counsel, Credence Systems Corporation**  
Title  
Registration No.: 39,320



Attorney Docket No.: CRDC-P0363

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**Patent**

In re Application of:

Inventor(s): Burnell G. West

Application No.: 10/056,287

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Art Unit:

For: CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT SYSTEM

Patent No.:

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**CERTIFICATE UNDER 37 CFR 3.73(b)**

CREDENCE SYSTEMS, a corporation, certifies that it is the assignee of the entire right, title and interest in the patent application identified above by virtue of either:

☐ An assignment from the inventor(s) of the patent application identified above. A copy of the assignment is attached.

☒ A chain of title from the inventor(s), of the patent application identified above, to the current assignees as shown below:

1. From: Burnell G. WEST To: Schlumberger Technologies, Inc.  
The document was recorded in the Patent and Trademark Office at  
Reel: 012541, Frame: 0016, or for which a copy thereof  
is attached.
2. From: Schlumberger Technologies, Inc To: NPTest, LLC  
The document was recorded in the Patent and Trademark Office at  
Reel: 014268, Frame: 0115, or for which a copy thereof  
is attached.
3. From: NPTest, LLC To: Credence Systems Corporation  
The document was recorded in the Patent and Trademark Office at  
Reel: 015242, Frame: 0574, or for which a copy thereof  
is attached.

☐ Additional documents in the chain of title are listed on a supplemental sheet.

☐ Copies of assignments or other documents in the chain of title are attached.

The undersigned has reviewed all the documents in the chain of title of the patent application identified above and, to the best of undersigned's knowledge and belief, title is in the assignee identified above.

The undersigned (whose title is supplied below) avers that the undersigned is empowered to sign this certificate on behalf of the assignee.

I hereby declare that all statements made herein of my own knowledge are true, and that all statements made on information and belief are believed to be true; and further, that these statements are made with the knowledge that willful false statements, and the like so made, are punishable by

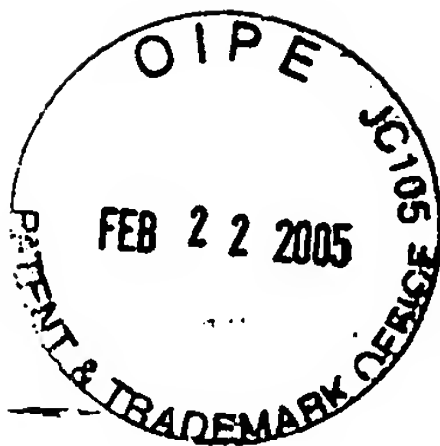
fine or imprisonment, or both, under Section 1001, Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

2/8/05  
Date

Naomi Obinata  
Signature

Naomi Obinata  
Typed or Printed Name

Assistant General Counsel/ Intellectual Property  
Title



P0363  
UNITED STATES DEPARTMENT OF COMMERCE  
Patent and Trademark Office  
ASSISTANT SECRETARY AND COMMISSIONER  
OF PATENTS AND TRADEMARKS  
Washington, D.C. 20231



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DENVER, CO 80202-5647

UNITED STATES PATENT AND TRADEMARK OFFICE  
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THE ENCLOSED DOCUMENT HAS BEEN RECORDED BY THE ASSIGNMENT DIVISION OF THE U.S. PATENT AND TRADEMARK OFFICE. A COMPLETE MICROFILM COPY IS AVAILABLE AT THE ASSIGNMENT SEARCH ROOM ON THE REEL AND FRAME NUMBER REFERENCED BELOW.

PLEASE REVIEW ALL INFORMATION CONTAINED ON THIS NOTICE. THE INFORMATION CONTAINED ON THIS RECORDATION NOTICE REFLECTS THE DATA PRESENT IN THE PATENT AND TRADEMARK ASSIGNMENT SYSTEM. IF YOU SHOULD FIND ANY ERRORS OR HAVE QUESTIONS CONCERNING THIS NOTICE, YOU MAY CONTACT THE EMPLOYEE WHOSE NAME APPEARS ON THIS NOTICE AT 703-308-9723. PLEASE SEND REQUEST FOR CORRECTION TO: U.S. PATENT AND TRADEMARK OFFICE, ASSIGNMENT DIVISION, BOX ASSIGNMENTS, CG-4, 1213 JEFFERSON DAVIS HWY, SUITE 320, WASHINGTON, D.C. 20231.

RECORDATION DATE: 10/13/2004

REEL/FRAME: 015242/0574  
NUMBER OF PAGES: 36

BRIEF: ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS).

ASSIGNOR:  
NPTEST, LLC

DOC DATE: 07/13/2004

ASSIGNEE:  
CREDENCE SYSTEMS CORPORATION  
1421 CALIFORNIA CIRCLE  
MILPITAS, CALIFORNIA 95035

SERIAL NUMBER: 09410569

FILING DATE: 10/01/1999  
ISSUE DATE:

PATENT NUMBER:

TITLE: TEST METHOD FOR SOURCE SYNCHRONOUS SIGNALS

SERIAL NUMBER: 09628116

FILING DATE: 07/28/2000  
ISSUE DATE:

PATENT NUMBER:

TITLE: SUPERCONDUCTING SINGLE PHOTON DETECTOR

CDB

DOCKETED

Date: 12-29-04  
Initials: /

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SERIAL NUMBER: 09676292

FILING DATE: 09/28/2000

PATENT NUMBER:

ISSUE DATE:

TITLE: METHOD AND APPARATUS FOR REMOTELY TESTING SEMICONDUCTORS

SERIAL NUMBER: 09679042

FILING DATE: 10/02/2000

PATENT NUMBER:

ISSUE DATE:

TITLE: METHOD AND APPARATUS FOR HIGH SPEED IC TEST INTERFACE

SERIAL NUMBER: 09746618

FILING DATE: 12/21/2000

PATENT NUMBER:

ISSUE DATE:

TITLE: OPTICAL COUPLING FOR TESTING INTEGRATED CIRCUITS

SERIAL NUMBER: 10056287

FILING DATE: 01/23/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT STREAM

SERIAL NUMBER: 10057134

FILING DATE: 01/24/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: COMPARATOR CIRCUIT FOR DIFFERENTIAL SWING COMPARISON AND COMMON-MODE VOLTAGE COMPARISON

SERIAL NUMBER: 10066123

FILING DATE: 01/30/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: PICA SYSTEM TIMING MEASUREMENT &amp; CALIBRATION

SERIAL NUMBER: 10079780

FILING DATE: 02/19/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: PICA SYSTEM DETECTOR CALIBRATION

SERIAL NUMBER: 10101564

FILING DATE: 03/18/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: TEST SYSTEM FORMATTERS

SERIAL NUMBER: 10102526

FILING DATE: 03/19/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: TEST SYSTEM ALGORITHMIC PROGRAM GENERATORS

SERIAL NUMBER: 10106280

FILING DATE: 03/25/2002

PATENT NUMBER: 6794861

ISSUE DATE: 09/21/2004

TITLE: METHOD AND APPARATUS FOR SOCKET CALIBRATION OF INTEGRATED CIRCUIT TESTERS

SERIAL NUMBER: 10136710

FILING DATE: 04/30/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: OPEN-LOOP FOR WAVEFORM ACQUISITION

SERIAL NUMBER: 10159527

FILING DATE: 05/30/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: SUB-RESOLUTION ALIGNMENT OF IMAGES

SERIAL NUMBER: 10161272

FILING DATE: 05/30/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: METHOD AND APPARATUS FOR DETERMINING THICKNESS OF A SEMICONDUCTOR SUBSTRATE AT THE FLOOR OF A TRENCH

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SERIAL NUMBER: 101760606

FILING DATE: 05/30/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: METHOD AND APPARATUS FOR FORMING A CAVITY IN A SEMICONDUCTOR  
SUBSTRATE USING A CHARGED PARTICLE BEAM

SERIAL NUMBER: 10288896

FILING DATE: 11/06/2002

PATENT NUMBER:

ISSUE DATE:

TITLE: PRECISE, IN-SITU ENDPOINT DETECTION FOR CHARGED PARTICLE BEAM  
PROCESSING

SERIAL NUMBER: 10371353

FILING DATE: 02/18/2003

PATENT NUMBER:

ISSUE DATE:

TITLE: SIGNAL PATHS PROVIDING MULTIPLE TEST CONFIGURATIONS

SERIAL NUMBER: 10382343

FILING DATE: 03/04/2003

PATENT NUMBER: 6781218

ISSUE DATE: 08/24/2004

TITLE: METHOD AND APPARATUS FOR ACCESSING INTERNAL NODES OF AN INTEGRATED  
CIRCUIT USING IC PACKAGE SUBSTRATE

SERIAL NUMBER: 10420675

FILING DATE: 04/21/2003

PATENT NUMBER:

ISSUE DATE:

TITLE: METHOD FOR SURFACE PREPARATION TO ENABLE UNIFORM ETCHING OF  
POLYCRYSTALLINE MATERIALS

SERIAL NUMBER: 10421059

FILING DATE: 04/23/2003

PATENT NUMBER:

ISSUE DATE:

TITLE: METHOD FOR BACKSIDE DIE THINNING AND POLISHING OF PACKAGED  
INTEGRATED CIRCUITS

SERIAL NUMBER: 10678438

FILING DATE: 10/03/2003

PATENT NUMBER:

ISSUE DATE:

TITLE: FIB MILLING OF COPPER OVER ORGANIC DIELECTRICS

SERIAL NUMBER: 10466366

FILING DATE: 12/08/2003

PATENT NUMBER:

ISSUE DATE:

TITLE: POWER SUPPLY DEVICE FOR A COMPONENT TESTING INSTALLATION

SERIAL NUMBER: 06472427

FILING DATE: 03/07/1983

PATENT NUMBER: 4594544

ISSUE DATE: 06/10/1986

TITLE: PARTICIPATE REGISTER FOR PARALLEL LOADING PIN-ORIENTED REGISTERS IN  
TEST EQUIPMENT

SERIAL NUMBER: 06611266

FILING DATE: 05/17/1984

PATENT NUMBER: 4651038

ISSUE DATE: 03/17/1987

TITLE: GATE HAVING TEMPERATURE - STABILIZED DELAY

SERIAL NUMBER: 06611454

FILING DATE: 05/17/1984

PATENT NUMBER: 4623802

ISSUE DATE: 11/18/1986

TITLE: MULTIPLE-STAGE GATE NETWORK HAVING INDEPENDENT REFERENCE VOLTAGE  
SOURCES



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SERIAL NUMBER: 06631958

PATENT NUMBER: 4673917

TITLE: METHOD AND APPARATUS FOR MINIMIZING DIGITAL-TO-ANALOG CONVERTER  
CORRECTION TRIMS

FILING DATE: 07/18/1984

ISSUE DATE: 06/16/1987

SERIAL NUMBER: 06766905

PATENT NUMBER: 4864228

TITLE: ELECTRON BEAM TEST PROBE FOR INTEGRATED CIRCUIT TESTING

FILING DATE: 08/16/1985

ISSUE DATE: 09/05/1989

SERIAL NUMBER: 06798592

PATENT NUMBER: 4706019

TITLE: ELECTRON BEAM TEST PROBE SYSTEM FOR ANALYZING INTEGRATED CIRCUITS

FILING DATE: 11/15/1985

ISSUE DATE: 11/10/1987

SERIAL NUMBER: 06828157

PATENT NUMBER: 4721909

TITLE: APPARATUS FOR PULSING ELECTRON BEAMS

FILING DATE: 02/10/1986

ISSUE DATE: 01/26/1988

SERIAL NUMBER: 06932762

PATENT NUMBER: 4795984

TITLE: MULTI-MARKER, MULTI-DESTINATION TIMING SIGNAL GENERATOR

FILING DATE: 11/19/1986

ISSUE DATE: 01/03/1989

SERIAL NUMBER: 07196776

PATENT NUMBER: 4912405

TITLE: MAGNETIC LENS AND ELECTRON BEAM DEFLECTION SYSTEM

FILING DATE: 05/17/1988

ISSUE DATE: 03/27/1990

SERIAL NUMBER: 07276359

PATENT NUMBER: 5054097

TITLE: METHODS AND APPARATUS FOR ALIGNMENT OF IMAGES

FILING DATE: 11/23/1988

ISSUE DATE: 10/01/1991

SERIAL NUMBER: 07284775

PATENT NUMBER: 4910698

TITLE: A SINE WAVE GENERATOR USING A CORDIC ALGORITHM

FILING DATE: 12/12/1988

ISSUE DATE: 03/20/1990

SERIAL NUMBER: 07553202

PATENT NUMBER: 5091693

TITLE: DUAL-SIDED TEST HEAD HAVING FLOATING CONTACT SURFACES

FILING DATE: 07/13/1990

ISSUE DATE: 02/25/1992

SERIAL NUMBER: 07577986

PATENT NUMBER: 5212443

TITLE: EVENT SEQUENCER FOR AUTOMATIC TEST EQUIPMENT

FILING DATE: 09/05/1990

ISSUE DATE: 05/18/1993

SERIAL NUMBER: 07577987

PATENT NUMBER: 5225772

TITLE: AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE

FILING DATE: 09/05/1990

ISSUE DATE: 07/06/1993

SERIAL NUMBER: 07640636

PATENT NUMBER: 5140164

TITLE: IC MODIFICATION WITH FOCUSED ION BEAM SYSTEM

FILING DATE: 01/14/1991

ISSUE DATE: 08/18/1992

SERIAL NUMBER: 07655255

PATENT NUMBER: 5127064

TITLE: HIGH RESOLUTION IMAGE COMPRESSION METHODS AND APPARATUS

FILING DATE: 02/13/1991

ISSUE DATE: 06/30/1992



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SERIAL NUMBER: 07710768

PATENT NUMBER: 5210487

TITLE: DOUBLE-GATED INTEGRATING SCHEME FOR ELECTRON BEAM TESTER

FILING DATE: 06/04/1991

ISSUE DATE: 05/11/1993

SERIAL NUMBER: 07729510

PATENT NUMBER: 5235273

TITLE: APPARATUS FOR SETTING PIN DRIVER/SENSOR REFERENCE VOLTAGE LEVEL

FILING DATE: 07/12/1991

ISSUE DATE: 08/10/1993

SERIAL NUMBER: 07732351

PATENT NUMBER: 5122988

TITLE: DATA STREAM SMOOTHING USING A FIFO MEMORY

FILING DATE: 07/17/1991

ISSUE DATE: 06/16/1992

SERIAL NUMBER: 07737553

PATENT NUMBER: 5144225

TITLE: METHODS AND APPARATUS FOR ACQUIRING DATA FROM INTERMITTENTLY FAILING CIRCUITS

FILING DATE: 07/25/1991

ISSUE DATE: 09/01/1992

SERIAL NUMBER: 07816639

PATENT NUMBER: 5392222

TITLE: LOCATING A FIELD OF VIEW IN WHICH SELECTED IC CONDUCTORS ARE UNOBSURED

FILING DATE: 12/30/1991

ISSUE DATE: 02/21/1995

SERIAL NUMBER: 07876566

PATENT NUMBER: 5475624

TITLE: TEST GENERATION BY ENVIRONMENT EMULATION

FILING DATE: 04/30/1992

ISSUE DATE: 12/12/1995

SERIAL NUMBER: 07928919

PATENT NUMBER: 5270643

TITLE: PULSED LASER PHOTOEMISSION ELECTRON-BEAM PROBE

FILING DATE: 08/12/1992

ISSUE DATE: 12/14/1993

SERIAL NUMBER: 07980371

PATENT NUMBER: 5357116

TITLE: FOCUSED ION BEAM PROCESSING WITH CHARGE CONTROL

FILING DATE: 11/23/1992

ISSUE DATE: 10/18/1994

SERIAL NUMBER: 08031547

PATENT NUMBER: 5604819

TITLE: DETERMINING OFFSET BETWEEN IMAGES OF AN IC

FILING DATE: 03/15/1993

ISSUE DATE: 02/18/1997

SERIAL NUMBER: 08037507

PATENT NUMBER: 5287022

TITLE: METHOD AND CIRCUIT FOR CONTROLLING VOLTAGE REFLECTIONS ON TRANSMISSION LINES

FILING DATE: 03/24/1993

ISSUE DATE: 02/15/1994

SERIAL NUMBER: 08062362

PATENT NUMBER: 5477139

TITLE: EVENT SEQUENCER FOR AUTOMATIC TEST EQUIPMENT

FILING DATE: 05/13/1993

ISSUE DATE: 12/19/1995

SERIAL NUMBER: 08100975

PATENT NUMBER: 5430400

TITLE: DRIVER CIRCUITS FOR IC TESTER

FILING DATE: 08/03/1993

ISSUE DATE: 07/04/1995

PATENT NUMBER: 5401972  
TITLE: LAYOUT OVERLAY FOR FIB OPERATIONS

ISSUE DATE: 03/15/1995

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SERIAL NUMBER: 08134330  
PATENT NUMBER: 5481550  
TITLE: APPARATUS FOR MAINTAINING STIMULATION TO A DEVICE UNDER TEST AFTER A TEST STOPS

FILING DATE: 10/12/1993

ISSUE DATE: 01/02/1996

SERIAL NUMBER: 08228027  
PATENT NUMBER: 5530372  
TITLE: METHOD OF PROBING A NET OF AN IC AT AN OPTIMAL PROBE-POINT

FILING DATE: 04/15/1994

ISSUE DATE: 06/25/1996

SERIAL NUMBER: 08267840  
PATENT NUMBER: 5461310  
TITLE: AUTOMATIC TEST EQUIPMENT SYSTEM USING PIN SLICE ARCHITECTURE

FILING DATE: 06/28/1994

ISSUE DATE: 10/24/1995

SERIAL NUMBER: 08268790  
PATENT NUMBER: 5616921  
TITLE: SELF-MASKING FIB MILLING

FILING DATE: 06/30/1994

ISSUE DATE: 04/01/1997

SERIAL NUMBER: 08434548  
PATENT NUMBER: 5700526  
TITLE: INSULATOR DEPOSITION USING FOCUSED ION BEAM

FILING DATE: 05/04/1995

ISSUE DATE: 12/23/1997

SERIAL NUMBER: 08488650  
PATENT NUMBER: 5638005  
TITLE: PREDICTIVE WAVEFORM ACQUISITION

FILING DATE: 06/08/1995

ISSUE DATE: 06/10/1997

SERIAL NUMBER: 08503023  
PATENT NUMBER: 5731984  
TITLE: NECTOR-BASED WAVEFORM ACQUISITION AND DISPLAY

FILING DATE: 07/17/1995

ISSUE DATE: 03/24/1998

SERIAL NUMBER: 08510397  
PATENT NUMBER: 5646521  
TITLE: ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER

FILING DATE: 08/01/1995

ISSUE DATE: 07/08/1997

SERIAL NUMBER: 08510395  
PATENT NUMBER: 5654657  
TITLE: ACCURATE ALIGNMENT OF CLOCKS IN MIXED-SIGNAL TESTER

FILING DATE: 08/01/1995

ISSUE DATE: 08/05/1997

SERIAL NUMBER: 08573071  
PATENT NUMBER: 5913022  
TITLE: LOADING HARDWARE PATTERN MEMORY IN AUTOMATIC TEST EQUIPMENT FOR TESTING CIRCUITS

FILING DATE: 12/15/1995

ISSUE DATE: 06/15/1999

SERIAL NUMBER: 08626484  
PATENT NUMBER: 5675499  
TITLE: OPTIMAL PROBE POINT PLACEMENT

FILING DATE: 04/02/1996

ISSUE DATE: 10/07/1997

SERIAL NUMBER: 08696346  
PATENT NUMBER: 5673275  
TITLE: ACCELERATED MODE TESTER TIMING

FILING DATE: 08/13/1996

ISSUE DATE: 09/30/1997

PATENT NUMBER: 5892949

ISSUE DATE: 04/06/1999

TITLE: ATE TEST PROGRAMMING ARCHITECTURE

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SERIAL NUMBER: 08710032

FILING DATE: 09/11/1996

PATENT NUMBER: 5745003

ISSUE DATE: 04/28/1998

TITLE: DRIVER CIRCUITS FOR IC TESTER

SERIAL NUMBER: 08734746

FILING DATE: 10/21/1996

PATENT NUMBER: 5747818

ISSUE DATE: 05/05/1998

TITLE: THERMOELECTRIC COOLING IN GAS-ASSISTED FIB SYSTEM

SERIAL NUMBER: 08734994

FILING DATE: 10/22/1996

PATENT NUMBER: 5918198

ISSUE DATE: 06/29/1999

TITLE: GENERATING PULSES IN ANALOG CHANNEL OF ATE TESTER

SERIAL NUMBER: 08745885

FILING DATE: 11/08/1996

PATENT NUMBER: 5959458

ISSUE DATE: 09/28/1999

TITLE: METHOD AND APPARATUS FOR MEASURING ELECTRICAL WAVEFORMS USING ATOMIC FORCE MICROSCOPY

SERIAL NUMBER: 08756296

FILING DATE: 11/25/1996

PATENT NUMBER: 6078845

ISSUE DATE: 06/20/2000

TITLE: SYSTEM, METHODS AND APPARATUS FOR STORING INFORMATION DURING A SEMICONDUCTOR MANUFACTURING PROCESS

SERIAL NUMBER: 08762395

FILING DATE: 12/09/1996

PATENT NUMBER: 5748124

ISSUE DATE: 05/05/1998

TITLE: ANALOG CHANNEL FOR MIXED-SIGNAL-VLSI TESTER

SERIAL NUMBER: 08762611

FILING DATE: 12/09/1996

PATENT NUMBER: 6061815

ISSUE DATE: 05/09/2000

TITLE: PROGRAM UTILITY REGISTER TO GENERATE ADDRESSES IN ALGORITHMIC PATTERN GENERATOR

SERIAL NUMBER: 08770621

FILING DATE: 12/19/1996

PATENT NUMBER: 5905266

ISSUE DATE: 05/18/1999

TITLE: CHARGED PARTICLE BEAM SYSTEM WITH OPTICAL MICROSCOPE

SERIAL NUMBER: 08771804

FILING DATE: 12/20/1996

PATENT NUMBER: 5840630

ISSUE DATE: 11/24/1998

TITLE: FBI ETCHING ENHANCED WITH 1,2 DI-iodo-ETHANE

SERIAL NUMBER: 08801687

FILING DATE: 02/18/1997

PATENT NUMBER: 5883905

ISSUE DATE: 03/16/1999

TITLE: PATTERN GENERATOR WITH EXTENDED REGISTER PROGRAMMING

SERIAL NUMBER: 08811104

FILING DATE: 03/03/1997

PATENT NUMBER: 5821549

ISSUE DATE: 10/13/1998

TITLE: THROUGH-THE-SUBSTRATE INVESTIGATION OF FLIP-CHIP IC'S

SERIAL NUMBER: 08818345

FILING DATE: 03/15/1997

PATENT NUMBER: 5905577

ISSUE DATE: 05/18/1999

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PAGE 009/019

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SERIAL NUMBER: 08841413  
PATENT NUMBER: 5920073  
TITLE: OPTICAL SYSTEM

FILING DATE: 04/22/1997  
ISSUE DATE: 07/06/1999

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SERIAL NUMBER: 08849290

FILING DATE: 05/14/1997

PATENT NUMBER: 6006346

ISSUE DATE: 12/21/1999

TITLE: METHOD AND EQUIPMENT FOR AUTOMATICALLY TESTING ELECTRONIC COMPONENTS

SERIAL NUMBER: 08858992

FILING DATE: 05/20/1997

PATENT NUMBER: 6014764

ISSUE DATE: 01/11/2000

TITLE: PROVIDING TEST VECTORS WITH PATTERN CHAINING DEFINITION

SERIAL NUMBER: 08930501

FILING DATE: 09/30/1997

PATENT NUMBER: 5996099

ISSUE DATE: 11/30/1999

TITLE: METHOD AND APPARATUS FOR AUTOMATICALLY TESTING ELECTRONIC COMPONENTS IN PARALLEL UTILIZING DIFFERENT TIMING SIGNALS FOR EACH ELECTRONIC COMPONENT

SERIAL NUMBER: 08930492

FILING DATE: 09/30/1997

PATENT NUMBER: 6049900

ISSUE DATE: 04/11/2000

TITLE: AUTOMATIC PARALLEL ELECTRONIC COMPONENT TESTING METHOD AND EQUIPMENT

SERIAL NUMBER: 08930490

FILING DATE: 09/30/1997

PATENT NUMBER: 5944846

ISSUE DATE: 08/31/1999

TITLE: METHOD AND APPARATUS FOR SELECTIVELY TESTING INDENTICAL PINS OF A PLURALITY OF ELECTRONIC COMPONENTS

SERIAL NUMBER: 08949747

FILING DATE: 10/14/1997

PATENT NUMBER: 6081484

ISSUE DATE: 06/27/2000

TITLE: MEASURING SIGNALS IN A TESTER SYSTEM

SERIAL NUMBER: 08977649

FILING DATE: 11/24/1997

PATENT NUMBER: 6128754

ISSUE DATE: 10/03/2000

TITLE: TESTER HAVING EVENT GENERATION CIRCUIT FOR ACQUIRING WAVEFORM BY SUPPLYING STROBE EVENTS FOR WAVEFORM ACQUISITION RATHER THAN USING STROBE EVENTS SPECIFIED BY THE TEST PROGRAM

SERIAL NUMBER: 09082455

FILING DATE: 05/20/1998

PATENT NUMBER: 6031229

ISSUE DATE: 02/29/2000

TITLE: AUTOMATIC SEQUENCING OF FIB OPERATIONS

SERIAL NUMBER: 09163710

FILING DATE: 09/30/1998

PATENT NUMBER: 6225626

ISSUE DATE: 05/01/2001

TITLE: THROUGH-THE- SUBSTRATE INVESTIGATION OF FLIP CHIP IC'S

SERIAL NUMBER: 09284939

FILING DATE: 04/22/1999

PATENT NUMBER: 6263464

ISSUE DATE: 07/17/2001

TITLE: DEVICE FOR CONTROLLING CONFORMITY OF CONSUMPTION OF AN ELECTRONIC COMPONENT IN A TESTING MACHINE

SERIAL NUMBER: 09350611

FILING DATE: 07/09/1999

PATENT NUMBER: 6694432

ISSUE DATE: 02/17/2004

TITLE: SECURING DATA IN A MACHINE FOR TESTING ELECTRONIC COMPONENTS

SERIAL NUMBER: 09419317

FILING DATE: 10/17/1999

PATENT NUMBER: 6661836

ISSUE DATE: 12/09/2003

TITLE: MEASURING JITTER OF HIGH-SPEED DATA CHANNELS

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SERIAL NUMBER: 09421784  
PATENT NUMBER: 6671845  
TITLE: PACKET-BASED DEVICE TEST SYSTEM

FILING DATE: 10/19/1999  
ISSUE DATE: 12/30/2003

SERIAL NUMBER: 09367376  
PATENT NUMBER: 6181117  
TITLE: POWER SUPPLY CIRCUIT OF AN ELECTRONIC COMPONENT IN A TEST MACHINE

FILING DATE: 10/25/1999  
ISSUE DATE: 01/30/2001

SERIAL NUMBER: 09440985  
PATENT NUMBER: 6410924  
TITLE: ENERGY FILTERED FOCUSED ION BEAM COLUMN

FILING DATE: 11/16/1999  
ISSUE DATE: 06/25/2002

SERIAL NUMBER: 09452058  
PATENT NUMBER: 6285963  
TITLE: MEASURING SIGNALS IN A TESTER SYSTEM

FILING DATE: 11/30/1999  
ISSUE DATE: 09/04/2001

SERIAL NUMBER: 09483463  
PATENT NUMBER: 6252222  
TITLE: DIFFERENTIAL PULSED LASER BEAM PROBING OF INTEGRATED CIRCUITS

FILING DATE: 01/13/2000  
ISSUE DATE: 06/26/2001

SERIAL NUMBER: 09500757  
PATENT NUMBER: 6496261  
TITLE: DOUBLE-PULSED OPTICAL INTERFEROMETER FOR WAVEFORM PROBING OF INTEGRATED CIRCUITS

FILING DATE: 02/08/2000  
ISSUE DATE: 12/17/2002

SERIAL NUMBER: 09510101  
PATENT NUMBER: 6553522  
TITLE: VALUATION OF TESTER ACCURACY

FILING DATE: 02/22/2000  
ISSUE DATE: 04/22/2003

SERIAL NUMBER: 09514708  
PATENT NUMBER: 6492797  
TITLE: SOCKET CALIBRATION METHOD AND APPARATUS

FILING DATE: 02/28/2000  
ISSUE DATE: 12/10/2002

SERIAL NUMBER: 09526979  
PATENT NUMBER: 6462814  
TITLE: BEAM DELIVERY AND IMAGING FOR OPTICAL PROBING OF A DEVICE OPERATING UNDER ELECTRICAL TEST

FILING DATE: 03/15/2000  
ISSUE DATE: 10/08/2002

SERIAL NUMBER: 09526407  
PATENT NUMBER: 6496953  
TITLE: CALIBRATION METHOD AND APPARATUS FOR CORRECTING PULSE WIDTH TIMING ERRORS IN INTEGRATED CIRCUIT TESTING

FILING DATE: 03/15/2000  
ISSUE DATE: 12/17/2002

SERIAL NUMBER: 09643576  
PATENT NUMBER: 6501706  
TITLE: TIME-TO-DIGITAL CONVERTER

FILING DATE: 08/22/2000  
ISSUE DATE: 12/31/2002

SERIAL NUMBER: 09648716  
PATENT NUMBER: 6622107  
TITLE: EDGE PLACEMENT AND JITTER MEASUREMENT FOR ELECTRONIC ELEMENTS

FILING DATE: 08/25/2000  
ISSUE DATE: 09/16/2003

SERIAL NUMBER: 09675090  
PATENT NUMBER: 6501288  
TITLE: ON-CHIP OPTICALLY TRIGGERED LATCH FOR IC TIME MEASUREMENTS

FILING DATE: 09/28/2000  
ISSUE DATE: 12/31/2002



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SERIAL NUMBER: 09675981  
PATENT NUMBER: 6630667  
TITLE: COMPACT, HIGH COLLECTION EFFICIENCY SCINTILLATOR FOR SECONDARY ELECTRON DETECTION

FILING DATE: 09/29/2000  
ISSUE DATE: 10/07/2003

p0322

SERIAL NUMBER: 09676144  
PATENT NUMBER: 6420888  
TITLE: TEST SYSTEM AND ASSOCIATED INTERFACE MODULE

FILING DATE: 09/29/2000  
ISSUE DATE: 07/16/2002

p0339

SERIAL NUMBER: 09696102  
PATENT NUMBER: 6748564  
TITLE: SCAN STREAM SEQUENCING FOR TESTING INTEGRATED CIRCUITS

FILING DATE: 10/24/2000  
ISSUE DATE: 06/08/2004

SERIAL NUMBER: 09781488  
PATENT NUMBER: 6518571  
TITLE: THROUGH-THE-SUBSTRATE INVESTIGATION OF FLIP-CHIP IC'S

FILING DATE: 02/10/2001  
ISSUE DATE: 02/11/2003

SERIAL NUMBER: 09871541  
PATENT NUMBER: 6514866  
TITLE: CHEMICALLY ENHANCED FOCUSED ION BEAM MICRO-MACHINING OF COPPER

FILING DATE: 05/31/2001  
ISSUE DATE: 02/04/2003

SERIAL NUMBER: 09924736  
PATENT NUMBER: 6672947  
TITLE: METHOD FOR GLOBAL DIE THINNING AND POLISHING OF FLIP-CHIP PACKAGED INTEGRATED CIRCUITS

FILING DATE: 08/07/2001  
ISSUE DATE: 01/06/2004

SERIAL NUMBER: 10004018  
PATENT NUMBER: 6737853  
TITLE: PHOTOCONDUCTIVE-SAMPLING VOLTAGE MEASUREMENT

FILING DATE: 10/18/2001  
ISSUE DATE: 05/18/2004

SERIAL NUMBER: 10132051  
PATENT NUMBER: 6522162  
TITLE: TEST SYSTEM HAVING INTERFACE MODULE

FILING DATE: 04/24/2002  
ISSUE DATE: 02/18/2003

p0339.D10

SERIAL NUMBER: 10197134  
PATENT NUMBER: 6744267  
TITLE: TEST SYSTEM AND METHODOLOGY

FILING DATE: 07/16/2002  
ISSUE DATE: 06/01/2004

JEFFREY OLSEN, EXAMINER  
ASSIGNMENT DIVISION  
OFFICE OF PUBLIC RECORDS



10/15/2004  
700122479

Docket No.:

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U.S. DEPARTMENT OF COMMERCE  
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## PATENTS ONLY

PTO-1556 (Modified)  
03-011  
No. 0651-0027 (rev. 5/31/2002)  
REV03

To the Director of the United States Patent and Trademark Office: Please record the attached original documents or copy thereof.

1. Name of conveying party(ies):

NPTest, LLC

Additional names(s) of conveying party(ies)

☐ Yes ☒ No

3. Nature of conveyance:

☒ Assignment☐ Merger☐ Security Agreement☐ Change of Name☐ Other

Execution Date: July 13, 2004

2. Name and address of receiving party(ies):

Name: Credence Systems CorporationAddress: 1121 California CircleCity: Milpitas State/Prov.: CACountry: U.S.A. ZIP: 95035

Additional name(s) &amp; address(es)

☐ Yes ☒ No

4. Application number(s) or patent numbers(s):

If this document is being filed together with a new application, the execution date of the application is:

Patent Application No.

Filing date

See Attachment A

B. Patent No.(s)

See Attachment A

Additional numbers

☒ Yes ☐ No

5. Name and address of party to whom correspondence concerning document should be mailed:

Name: Gregory P. Durbin, Esq.Registration No. 42,503Address: DORSEY & WHITNEY LLP370 Seventeenth Street, Suite 4700City: Denver State/Prov.: COCountry: U.S.A. ZIP: 80202-5647

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6. Total number of applications and patents involved:

112

7. Total fee (37 CFR 3.41):.....\$ 4,480.00☐ Enclosed - Any excess or insufficiency should be credited or debited to deposit account☒ Authorized to be charged to deposit account

8. Deposit account number:

04-1415

(Attach duplicate copy of this page if paying by deposit account)

9. Statement and signature.

To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.

Gregory P. Durbin

Name of Person Signing

Signature

36

Date

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Country	Application No.	App. No.	Grant Date	Patent No.	Title	Status	Doc#
United States	03/07/1983	472,427	06/10/1986	4,594,544	Participate Register for Parallel Loading Pin-Oriented Registers in Test Equipment	Inactive	P0081
United States	05/17/1984	611,266	03/17/1987	4,651,038	Gate Having Temperatures-Stabilized Delay	Granted	P0117
United States	05/17/1984	611,454	11/18/1986	4,623,802	Multiple-Stage Gate Network Having Independent Reference Voltage Sources	Inactive	P0118
United States	07/18/1984	631,958	06/16/1987	4,673,917	Method and Apparatus for Minimizing Digital-To-Analog Converter Correction Trims	Granted	P0120
United States	08/16/1985	766,905	09/05/1989	4,864,228	Electron Beam Test Probe for Integrated Circuit Testing	Granted	P0150
United States	11/15/1985	798,592	11/10/1987	4,706,019	Electron Beam Test Probe System for Analyzing Integrated Circuits	Granted	P0132
United States	02/10/1986	828,157	01/26/1988	4,721,909	Apparatus for Pulsing Electron Beams	Granted	P0133
United States	11/19/1986	932,762	01/03/1989	4,795,984	Multi-Marker, Multi-Destination Timing Signal Generator	Granted	P0125
United States	05/17/1988	196,776	03/27/1990	4,912,405	Magnetic Lens and Electron Beam Deflection System	Granted	P0135
United States	11/13/1988	276,359	10/01/1991	5,054,097	Methods and Apparatus for Alignment of Images	Granted	P0165
United States	12/12/1988	284,775	03/20/1990	4,910,698	Sine Wave Generator Using A Cordic Algorithm	Granted	P0128
United States	07/13/1990	553,202	02/25/1992	5,091,693	Dual-Sided Test Head Having Floating Contact Surfaces	Granted	P0180
United States	09/05/1990	577,986	05/18/1993	5,212,443	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	09/05/1990	577,987	07/06/1993	5,225,772	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	01/14/1991	640,636	08/18/1992	5,140,164	IC Modification with Focused ION Beam	Inactive	P0189
United States	02/13/1991	07/655,255	06/30/1992	5,127,064	High Resolution Image Compression Methods and Apparatus	Granted	P0164
United States	06/04/1991	07/710,768	05/11/1993	5,210,487	Double-Gated Integrating Scheme for Electron Beam Tester	Granted	P0191
United States	07/12/1991	729,510	08/10/1993	5,235,273	Apparatus for Setting Pin Driver/Sensor Reference Voltage Level	Granted	P0194
United States	07/17/1991	732,351	06/16/1992	5,100,000	Data Stream Smoothing using a FIFO Memory	Granted	P0172
United States	07/25/1991	737,553	09/01/1992	5,144,225	Methods and Apparatus for Acquiring Data from Intermittently Failing Circuits	Granted	P0173
United States	12/30/1991	816,639	02/21/1995	5,392,222	Locating a Field of View in which Selected IC Conductors are Unobscured	Granted	P0184
United States	04/30/1992	876,566	12/12/1995	5,475,624	Test Generation by Environment Emulation	Granted	P0192

U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CRENDENCE SYSTEMS CORPORATION

Country	Application No.	Grant Date	Patent No.	Title	Status	Notes
United States	08/12/1992	07/928,919	5,270,643	Pulsed Laser Photoemission Electron-Beam Probe	Granted	P0188
United States	11/23/1992	07/980,371	5,357,116	Focused ION Beam Processing with Charge Control	Granted	P0204
United States	03/15/1993	031,547	5,604,819	Determining Offset between Images of an IC	Granted	P0202
United States	03/24/1993	037,507	5,287,022	Method and Circuit for Controlling Voltage Reflections on Transmissions Lines	Granted	P0193
United States	05/13/1993	62,362	5,477,139	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	08/03/1993	100,975	5,430,400	Driver Circuits for IC Tester	Granted	P0209
United States	09/02/1993	08/115,997	5,401,972	Layout Overlay for FIB Operations	Granted	P0210
United States	10/12/1993	08/134,330	5,481,550	Apparatus For Maintaining Stimulation To A Device Under Test After A Test Stops	Granted	P0203
United States	04/15/1994	228,027	5,530,372	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	06/28/1994	08/267,870	5,461,310	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	06/30/1994	268,790	5,616,921	Self-Masking FIB Milling	Granted	P0207
United States	05/04/1995	08/434,548	5,700,526	Insulator Deposition Using Focused Ion Beam	Granted	P0234
United States	06/08/1995	08/488,650	5,638,005	Predictive Waveform Acquisition	Granted	P0216
United States	07/17/1995	08/503,023	5,731,984	Vector-Based Waveform Acquisition and Display	Granted	P0239
United States	08/01/1995	08/510,397	5,646,521	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	08/01/1995	08/510,395	5,654,657	Accurate Alignment of Clocks in Mixed-Signal Tester	Granted	P0228
United States	12/15/1995	08/573,071	5,913,022	Loading Hardware Pattern Memory in Automatic Test Equipment for Testing Circuits	Granted	P0231
United States	04/02/1996	626,484	5,675,499	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	08/13/1996	08/696,346	5,673,275	Accelerated Mode Tester Timing	Granted	P0220
United States	08/30/1996	705,795	5,892,949	ATE Test Programming Architecture	Granted	P0233
United States	09/11/1996	110,032	5,747,818	Driver Circuits for IC Tester	Granted	P0243
United States	10/21/1996	08/734,746	5,747,818	Thermoelectric Cooling Gas-Assisted FIB System	Granted	P0245
United States	10/22/1996	08/734,994	5,918,198	Generating Pulses in Analog Channel of ATE Tester	Granted	P0252



ATTACHMENT A  
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEX SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Patent No.
United States	11/08/1996	08/745,885	09/28/1999	5,959,458	Method and Apparatus for Measuring Electrical Waveforms using Atomic Force Microscopy	Granted	P0253
United States	11/25/1996	08/756,296	06/20/2000	6,078,845	Apparatus for Carrying Semiconductor Devices	Granted	P0257
United States	12/09/1996	08/762,395	05/05/1998	5,748,124	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	12/09/1996	08/762,611	05/09/2000	6,061,815	Programming Utility Register to Generate Addresses in Algorithmic Pattern Generator	Granted	P0247
United States	12/19/1996	08/770,621	05/18/1999	5,905,266	Charged Particle Beam System with Optical Microscope	Granted	P0248
United States	12/20/1996	08/771,804	11/24/1998	5,840,630	FIB Etching Enhanced with 1,2 Di-Iodo-Ethane	Granted	P0244
United States	02/18/1997	08/801,687	03/16/1999	5,883,905	Pattern Generator with Extended Register Programming	Granted	P0266
United States	03/03/1997	08/811,104	10/13/1998	5,821,549	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	03/15/1997	08/818,345	05/18/1999	5,905,677	Dual-Laser Voltage Probing of ICs	Granted	P0261
United States	04/22/1997	08/841,413	07/06/1999	5,920,073	Optical System with an Axially Moveable Apertured Plate	Granted	P0262
United States	05/14/1997	849,290	12/21/1999	6,006,346	Method and Equipment for Automatically Testing Electronic Components	Granted	P0221
United States	05/20/1997	08/858,992	01/11/2000	6,014,764	Providing Test Vectors with Pattern Chaining Definition	Granted	P0254
United States	09/30/1997	08/930,501	11/30/1999	5,996,099	Method and Apparatus for Automatically Testing Electronic Components in Parallel Utilizing Different Timing Signals for each Electronic Component	Granted	P0236
United States	09/30/1997	09/930,492	04/11/2000	6,049,900	Automatic Parallel Electronic Component Testing Method and Equipment	Granted	P0297
United States	09/30/1997	08/930,490	08/31/1999	5,944,846	Method and Apparatus for Selectively Testing Identical Pins of a Plurality of Electronic Components	Granted	P0238
United States	10/14/1997	08/949,747	06/27/2000	6,081,484	Measuring Signals in a Tester System	Granted	P0274
United States	11/24/1997	08/977,649	10/03/2000	6,128,754	Automatic Circuit Tester Having a Waveform Acquisition Mode of Operation	Granted	P0271
United States	05/20/1998	09/082,455	02/29/2000	6,031,229	Automatic Sequencing of FIB Operations	Granted	P0269
United States	09/30/1998	09/163,710	05/01/2001	6,225,626	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246

AT MACHINES, INC.

## U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CRESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Granted Date	Patent No.	Title	Status	Booklet
United States	04/22/1999	09/284,939	07/17/2001	6,263,464	Device for Controlling Conformity of Consumption of an Electronic Component in a Testing Machine	Granted	P0263
United States	07/09/1999	09/350,611	02/17/2004	6,694,432	Securing Data in a Machine for Testing Electronic Components	Granted	P0291
United States	10/01/1999	09/410,569	---	---	Test Method and Apparatus for Source Synchronous Signals	Inactive	P0309
United States	10/17/1999	09/419,317	12/09/2003	6,661,836	Measuring Jitter of High-Speed Data Channels	Granted	P0299
United States	10/19/1999	09/421,784	12/30/2003	6,671,845	Packet-Based Device Test System	Granted	P0306
United States	10/25/1999	367,376	01/30/2001	6,181,117	Power Supply Circuit of an Electronic Component in a Test Machine	Granted	P0264
United States	11/16/1999	09/440,985	06/25/2002	6,410,924	Energy Filtered Focused Ion Beam Column	Granted	P0281
United States	11/30/1999	09/452,058	09/04/2001	6,285,963	Measuring Signals in a Tester System	Granted	P0274
United States	01/13/2000	09/483,463	06/26/2001	6,252,222	Differential Pulsed Laser Beam Probing of Integrated Circuits	Granted	P0312
United States	02/08/2000	09/500,757	12/17/2002	6,496,261	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	Granted	P0316
United States	02/22/2000	09/510,101	04/22/2003	6,553,522	Valuation of Tester Accuracy	Granted	P0303
United States	02/28/2000	09/514,708	12/10/2002	6,492,797	Socket Calibration Method and Apparatus	Granted	P0302
United States	03/15/2000	09/526,979	10/08/2002	6,462,814	Beam Delivery and Imaging for Optical Probing of a Device Operating under Electrical Test	Granted	P0267
United States	03/15/2000	09/526,407	12/17/2002	6,496,953	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	Granted	P0307
United States	07/28/2000	09/628,116	---	---	Superconducting Single Photon Detector	Pending	P0332
United States	08/22/2000	09/643,576	12/31/2002	6,501,706	Time-To-Digital Converter	Granted	P0296
United States	08/25/2000	09/648,715	09/16/2003	6,622,107	Edge Placement and Jitter Measurement for Electronic Elements	Granted	P0297
United States	09/28/2000	09/675,090	12/31/2002	6,501,288	On-Chip Optically Triggered Latch for IC Time Measurements	Granted	P0324
United States	09/28/2000	09/676,292	---	---	Method and Apparatus for Remotely Testing Semiconductor	Pending	P0340
United States	09/29/2000	09/675,981	10/07/2003	6,630,667	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	Granted	P0322
United States	09/29/2000	09/676,144	07/16/2002	6,420,888	Test Interface Module	Granted	P0339
United States	10/02/2000	09/679,042	---	---	Method and Apparatus for High Speed IC Test Interface	Pending	P0337

## U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDDENCE SYSTEMS CORPORATION

Country	Application No.	Application Date	Granted Date	Patent No.	Abstract	Status	Patent No.
United States	09/696,102	10/24/2000	06/08/2004	6,748,564	Scan Stream Sequencing for Testing Integrated Circuits	Granted	P0321
United States	09/746,618	12/21/2000	---	---	Optical Coupling for Testing Integrated Circuits	Pending	P0329
United States	09/781,488	02/10/2001	02/11/2003	6,518,571	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	09/871,541	05/31/2001	02/04/2003	6,514,866	Chemical Enhanced Focused Ion Beam Micro-Machining of Copper	Granted	P0345
United States	09/924,736	08/07/2001	01/06/2004	6,672,947	Method for Global Die Thinning and Polishing of Flip-Chip Packaged Integrated Circuits	Granted	P0338
United States	10/004,018	10/18/2001	05/18/2004	6,737,853	Photoconductive-Sampling Voltage Measurement	Granted	P0272
United States	10/056,287	01/23/2002	---	---	Circuit and Method for Distributing Events in an Event Stream	Pending	P0363
United States	10/057,134	01/24/2002	---	---	Comparator Circuit for Differential Swing Comparison and Common-Mode Voltage Comparison	Pending	P0364
United States	10/066,123	01/30/2002	---	---	PICA System Timing Measurement & Calibration	Pending	P0372
United States	10/079,780	02/19/2002	---	---	PICA System Detector Calibration	Pending	P0373
United States	10/101,564	03/18/2002	---	---	Test System Formatters	Pending	P0348
United States	10/102,526	03/19/2002	---	---	Test System Algorithmic Program Generators	Pending	P0350
United States	10/105,280	03/25/2002	---	---	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	Pending	P0352
United States	10/132,051	04/24/2002	02/18/2003	6,522,162	Test System Having Interface Module	Granted	P0339
United States	10/136,710	04/30/2002	---	---	Open-Loop for Waveform Acquisition	Pending	P0355
United States	10/159,527	05/30/2002	---	---	Sub-Resolution Alignment of Images	Pending	P0356
United States	10/161,272	05/30/2002	---	---	Method and Apparatus for Determining Thickness of a Semiconductor Substrate at the Floor	Pending	P0365
United States	10/160,606	05/30/2002	---	---	Method and Apparatus for Forming a Trench Through a Semiconductor Substrate	Pending	P0369
United States	10/197,134	07/16/2002	06/01/2004	6,744,207	Test System and Methodology	Granted	P0370
United States	10/288,896	11/06/2002	---	---	Precise, In-situ Endpoint Detection for Charged Particle Beam	Pending	P0311
United States	10/371,353	02/18/2003	---	---	Signal Paths Providing Multiple Test Configurations	Pending	P0374



ATTACHMENT A  
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Filing Date	Application No.	Grant Date	Patent No.	Title	Status	Patent No.
United States	03/04/2003	10/382,343	---	---	Method and Apparatus for Accessing Internal Nodes of an Integrated Circuit Using IC Package Substrate	Pending	P0318
United States	04/21/2003	10/420,675	---	---	Method for Surface Preparation to Enable Uniform Etching of Polycrystalline Materials	Pending	P0382
United States	04/23/2003	10/421,059	---	---	Method for Backside Die Thinning and Polishing of Packaged Integrated Circuits	Pending	P0338
United States	10/03/2003	10/678,438	---	---	PIB Milling of Copper over Organic Dielectrics	Pending	P0395
United States	12/08/2003	10/466,366	---	---	Power Supply Device for a Component Testing Installation	Pending	P0353



## PATENT ASSIGNMENT

WHEREAS, NPTest, LLC, a limited liability company organized and existing under the laws of the State of Delaware, and having its principal place of business at 150 Baytech Drive, San Jose, California 95134, United States of America (the "Assignor"), is the owner of all right, title, and interest in and to the United States and foreign patents and patent applications (the "Patent Rights") listed in Annex A and Annex B hereto; and

WHEREAS, Credence Systems Corporation, a corporation organized and existing under the laws of the State of Delaware, and having its principal place of business at 1421 California Circle, Milpitas, California 95035, United States of America (the "Assignee"), is desirous of acquiring the entire right, title, and interest in and to said Patent Rights;

WHEREAS, Assignor desires to assign and Assignee desires to receive all of Assignor's right, title and interest in and to the Patent Rights;

NOW THEREFORE, for the sum of \$1.00 and other good and valuable consideration to it in hand paid, the receipt and sufficiency of which are hereby acknowledged, Assignor has sold, assigned, and set over and by these presents does hereby sell, assign and transfer to the said Assignee, and said Assignee's legal representatives, successors and assigns, any and all of the entire right, title and interest in and to said Patent Rights, any applications, provisionals, non-provisionals, continuations, continuations-in-part, continuing prosecutions, divisionals, renewals, or substitutes thereof, all international, foreign and regional applications corresponding thereto, all convention rights corresponding thereto, all priority rights and claims corresponding thereto, and the Letters Patent, both foreign and domestic, that may or shall issue thereon, or any reissues or reexaminations thereof, to be obtained for the Patent Rights;

UPON SAID CONSIDERATION, the Assignor hereby covenants and agrees with the said Assignee that it will not execute any writing or do any act whatsoever conflicting with these presents, and that it will, at any time upon request, without further or additional consideration, but at the expense of the said Assignee, execute such additional assignments and other writings and do such additional acts as said Assignee may deem necessary or desirable to perfect the Assignee's enjoyment of this grant, and render all necessary assistance in making application for and obtaining original, provisionals, non-provisionals, continuations, continuations-in-part, continuing prosecutions, divisionals, renewals, reissued, reexamined or extended Letters Patent of the United States, or of any and all foreign countries, on said Patent Rights, and in enforcing any rights or choses in action accruing as a result of such applications or patents, by giving testimony in any proceedings or transactions involving such applications or patents, and by executing preliminary statements and other affidavits, it being understood that the foregoing covenant and agreement shall bind, and inure to the benefit of, the assigns and legal representatives of both parties.

IN WITNESS WHEREOF, the Assignor has executed this Assignment and caused the same to be duly delivered on its behalf on the day and year first set forth below.

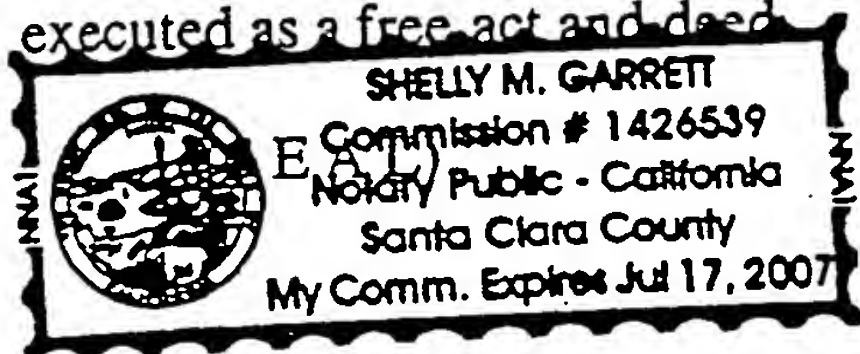
NPTEST, LLC

Date July 12, 2004

By: [Signature]  
Name: Leslie Weise  
Title: General Counsel and Secretary

STATE OF CALIFORNIA )  
 ) ss.  
COUNTY OF SANTA CLARA)

On this 12 day of July, 2004, before me a Notary Public, personally appeared Leslie Weise, the above-mentioned representative of the Assignor, - NPTest, LLC, who executed the foregoing Assignment, and represented and acknowledged that he/she had the requisite corporate authority to execute this Assignment and the same was executed as a free act and deed.



[Signature]  
Notary Public

My commission expires: July 17, 2007

IN WITNESS WHEREOF, Assignee confirms the acceptance of the assignment of the Patent Rights from the Assignor.

CREDENCE SYSTEMS CORPORATION

Date 7/13/04

By: [Signature]  
Name: Byron Milstead  
Title: Vice President and General Counsel

STATE OF CALIFORNIA )  
 ) ss.  
COUNTY OF SANTA CLARA)

On this 13 day of July, 2004, before me a Notary Public, personally appeared Byron Milstead, the above-mentioned representative of the Assignee, Credence Systems Corporation, who executed the foregoing Patent Assignment, and represented

and acknowledged that he/she had the requisite corporate authority to execute and accept this Patent Assignment and the same was executed as a free act and deed.

(S E A L)

Shelly M. Garrett  
Notary Public

My commission expires: July 17, 2007



Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	03/07/1983	472,427	06/10/1986	4,594,544	Participate Register for Parallel Loading Pin-Oriented Registers In Test Equipment	Inactive	P0081

REDACTED

United States	05/17/1984	611,266	03/17/1987	4,651,038	Gate Having Temperatures-Stabilized Delay	Granted	P0117
United States	05/17/1984	611,454	11/18/1986	4,623,802	Multiple-Stage Gate Network Having Independent Reference Voltage Sources	Inactive	P0118
United States	07/18/1984	631,958	06/16/1987	4,673,917	Method and Apparatus for Minimizing Digital-To-Analog Converter Correction Trims	Granted	P0120
United States	08/16/1985	766,905	09/05/1989	4,864,228	Electron Beam Test Probe for Integrated Circuit Testing	Granted	P0150
United States	11/15/1985	798,592	11/10/1987	4,706,019	Electron Beam Test Probe System for Analyzing Integrated Circuits	Granted	P0132
United States	02/10/1986	828,157	01/26/1988	4,721,909	Apparatus for Pulsing Electron Beams	Granted	P0133
United States	11/19/1986	932,762	01/03/1989	4,795,984	Multi-Marker, Multi-Destination Timing Signal Generator	Granted	P0125

REDACTED

United States	05/17/1988	196,776	03/27/1990	4,912,405	Magnetic Lens and Electron Beam Deflection System	Granted	P0135
United States	11/13/1988	276,359	10/01/1991	5,054,097	Methods and Apparatus for Alignment of Images	Granted	P0165
United States	12/12/1988	284,775	03/20/1990	4,910,698	Sine Wave Generator Using A Cordic Algorithm	Granted	P0128
United States	07/13/1990	553,202	02/25/1992	5,091,693	Dual-Sided Test Head Having Floating Contact Surfaces	Granted	P0180
United States	09/05/1990	577,986	05/18/1993	5,212,443	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	09/05/1990	577,987	07/06/1993	5,225,772	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	01/14/1991	640,636	08/18/1992	5,140,164	IC Modification with Focused ION Beam	Inactive	P0189
United States	02/13/1991	07/655,255	06/30/1992	5,127,064	High Resolution Image Compression Methods and Apparatus	Granted	P0164
United States	06/04/1991	07/710,768	05/11/1993	5,210,487	Double-Gated Integrating Scheme for Electron Beam Tester	Granted	P0191
United States	07/12/1991	729,510	08/10/1993	5,235,273	Apparatus for Setting Pin Driver/Sensor Reference Voltage Level	Granted	P0194



**U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CRENDENCE SYSTEMS CORPORATION**

<u>Country</u>	<u>Application Date</u>	<u>Application No.</u>	<u>Grant Date</u>	<u>Patent No.</u>	<u>Title</u>	<u>Status</u>	<u>Docket</u>
United States	07/17/1991	732,351	06/16/1992	5,122,988	Data Stream Smoothing using a FIFO Memory	Granted	P0172
United States	07/25/1991	737,553	09/01/1992	5,144,225	Methods and Apparatus for Acquiring Data from Intermittently Failing Circuits	Granted	P0173
United States	12/30/1991	816,639	02/21/1995	5,392,222	Locating a Field of View in which Selected IC Conductors are Unobscured	Granted	P0184
United States	04/30/1992	876,566	12/12/1995	5,475,624	Test Generation by Environment Emulation	Granted	P0192
United States	08/12/1992	07/928,919	12/14/1993	5,270,643	Pulsed Laser Photoemission Electron-Beam Probe	Granted	P0188
United States	11/23/1992	07/980,371	10/18/1994	5,357,116	Focused ION Beam Processing with Charge Control	Granted	P0204
United States	03/15/1993	031,547	02/18/1997	5,604,819	Determining Offset between Images of an IC	Granted	P0202
United States	03/24/1993	037,507	02/15/1994	5,287,022	Method and Circuit for Controlling Voltage Reflections on Transmissions Lines	Granted	P0193
United States	05/13/1993	62,362	12/19/1995	5,477,139	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	08/03/1993	100,975	07/04/1995	5,430,400	Driver Circuits for IC Tester	Granted	P0209
United States	09/02/1993	08/115,997	03/28/1995	5,401,972	Layout Overlay for FIB Operations	Granted	P0210
United States	10/12/1993	08/134,330	01/02/1996	5,481,550	Apparatus For Maintaining Stimulation To A Device Under Test After A Test Stops	Granted	P0203
United States	04/15/1994	228,027	06/25/1996	5,530,372	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	06/28/1994	08/267,870	10/24/1995	5,461,310	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	06/30/1994	268,790	04/01/1997	5,616,921	Self-Masking FIB Milling	Granted	P0207
United States	05/04/1995	08/434,548	12/23/1997	5,700,526	Insulator Deposition Using Focused Ion Beam	Granted	P0234
United States	06/08/1995	08/488,650	06/10/1997	5,638,005	Predictive Waveform Acquisition	Granted	P0216
United States	07/17/1995	08/503,023	03/24/1998	5,731,984	Vector-Based Waveform Acquisition and Display	Granted	P0239
United States	08/01/1995	08/510,397	07/08/1997	5,646,521	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	08/01/1995	08/510,395	08/05/1997	5,654,657	Accurate Alignment of Clocks in Mixed-Signal Tester	Granted	P0228
<b>REDACTED</b>							
United States	12/15/1995	08/573,071	06/15/1999	5,913,022	Loading Hardware Pattern Memory in Automatic Test Equipment for Testing Circuits	Granted	P0231
United States	04/02/1996	626,484	10/07/1997	5,675,499	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	08/13/1996	08/696,346	09/30/1997	5,673,275	Accelerated Mode Tester Timing	Granted	P0220
United States	08/30/1996	705,795	04/06/1999	5,892,949	ATE Test Programming Architecture	Granted	P0233
United States	09/11/1996	710,032	04/28/1998	5,745,003	Driver Circuits for IC Tester	Granted	P0243
United States	10/21/1996	08/734,746	05/05/1998	5,747,818	Thermoelectric Cooling Gas-Assisted FIB System	Granted	P0245
United States	10/22/1996	08/734,994	06/29/1999	5,918,198	Generating Pulses in Analog Channel of ATE Tester	Granted	P0252
United States	11/08/1996	08/745,885	09/28/1999	5,959,458	Method and Apparatus for Measuring Electrical Waveforms using Atomic Force Microscopy	Granted	P0253
United States	11/25/1996	08/756,296	06/20/2000	6,078,845	Apparatus for Carrying Semiconductor Devices	Granted	P0257
United States	12/09/1996	08/762,395	05/05/1998	5,748,124	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	12/09/1996	08/762,611	05/09/2000	6,061,815	Programming Utility Register to Generate Addresses in Algorithmic Pattern Generator	Granted	P0247
United States	12/19/1996	08/770,621	05/18/1999	5,905,266	Charged Particle Beam System with Optical Microscope	Granted	P0248
United States	12/20/1996	08/771,804	11/24/1998	5,840,630	FIB Etching Enhanced with 1,2 Di-Iodo-Ethane	Granted	P0244
REDACTED							
United States	02/18/1997	08/801,687	03/16/1999	5,883,905	Pattern Generator with Extended Register Programming	Granted	P0266
United States	03/03/1997	08/811,104	10/13/1998	5,821,549	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	03/15/1997	08/818,345	05/18/1999	5,905,577	Dual-Laser Voltage Probing of ICs	Granted	P0261
United States	04/22/1997	08/841,413	07/06/1999	5,920,073	Optical System with an Axially Moveable Apertured Plate	Granted	P0262
United States	05/14/1997	849,290	12/21/1999	6,006,346	Method and Equipment for Automatically Testing Electronic Components	Granted	P0221
United States	05/20/1997	08/858,992	01/11/2000	6,014,764	Providing Test Vectors with Pattern Chaining Definition	Granted	P0254
United States	09/30/1997	08/930,501	11/30/1999	5,996,099	Method and Apparatus for Automatically Testing Electronic Components in Parallel Utilizing Different Timing Signals for each Electronic Component	Granted	P0236
United States	09/30/1997	09/930,492	04/11/2000	6,049,900	Automatic Parallel Electronic Component Testing Method and Equipment	Granted	P0237



**U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS, LLC**

<u>Country</u>	<u>Application Date</u>	<u>Application No.</u>	<u>Grant Date</u>	<u>Patent No.</u>	<u>Title</u>	<u>Status</u>	<u>Docket</u>
United States	09/30/1997	08/930,490	08/31/1999	5,944,846	Method and Apparatus for Selectively Testing Identical Pins of a Plurality of Electronic Components	Granted	P0238
United States	10/14/1997	08/949,747	06/27/2000	6,081,484	Measuring Signals in a Tester System	Granted	P0274
United States	11/24/1997	08/977,649	10/03/2000	6,128,754	Automatic Circuit Tester Having a Waveform Acquisition Mode of Operation	Granted	P0271
United States	05/20/1998	09/082,455	02/29/2000	6,031,229	Automatic Sequencing of FIB Operations	Granted	P0269
United States	09/30/1998	09/163,710	05/01/2001	6,225,626	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	04/22/1999	09/284,939	07/17/2001	6,263,464	Device for Controlling Conformity of Consumption of an Electronic Component in a Testing Machine	Granted	P0263
United States	07/09/1999	09/350,611	02/17/2004	6,694,432	Securing Data in a Machine for Testing Electronic Components	Granted	P0291
United States	10/01/1999	09/410,569	---	---	Test Method and Apparatus for Source Synchronous Signals	Inactive	P0309
United States	10/17/1999	09/419,317	12/09/2003	6,661,836	Measuring Jitter of High-Speed Data Channels	Granted	P0299
United States	10/19/1999	09/421,784	12/30/2003	6,671,845	Packet-Based Device Test System	Granted	P0306
United States	10/25/1999	367,376	01/30/2001	6,181,117	Power Supply Circuit of an Electronic Component in a Test Machine	Granted	P0264
United States	11/16/1999	09/440,985	06/25/2002	6,410,924	Energy Filtered Focused Ion Beam Column	Granted	P0281
United States	11/30/1999	09/452,058	09/04/2001	6,285,963	Measuring Signals in a Tester System	Granted	P0274
United States	01/13/2000	09/483,463	06/26/2001	6,252,222	Differential Pulsed Laser Beam Probing of Integrated Circuits	Granted	P0312
United States	02/08/2000	09/500,757	12/17/2002	6,496,261	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	Granted	P0316
United States	02/22/2000	09/510,101	04/22/2003	6,553,522	Valuation of Tester Accuracy	Granted	P0303
United States	02/28/2000	09/514,708	12/10/2002	6,492,797	Socket Calibration Method and Apparatus	Granted	P0302
United States	03/15/2000	09/526,979	10/08/2002	6,462,814	Beam Delivery and Imaging for Optical Probing of a Device Operating under Electrical Test	Granted	P0267
United States	03/15/2000	09/526,407	12/17/2002	6,496,953	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	Granted	P0307
United States	07/28/2000	09/628,116	---	---	Superconducting Single Photon Detector	Pending	P0332
United States	08/22/2000	09/643,576	12/31/2002	6,501,706	Time-To-Digital Converter	Granted	P0296
United States	08/25/2000	09/648,716	09/16/2003	6,622,107	Edge Placement and Jitter Measurement for Electronic Elements	Granted	P0297



Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	09/28/2000	09/675,090	12/31/2002	6,501,288	On-Chip Optically Triggered Latch for IC Time Measurements	Granted	P0324
United States	09/28/2000	09/676,292	---	---	Method and Apparatus for Remotely Testing Semiconductor	Pending	P0340
United States	09/29/2000	09/675,981	10/07/2003	6,630,667	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	Granted	P0322
United States	09/29/2000	09/676,144	07/16/2002	6,420,888	Test Interface Module	Granted	P0339
United States	10/02/2000	09/679,042	---	---	Method and Apparatus for High Speed IC Test Interface	Pending	P0337
United States	10/24/2000	09/696,102	06/08/2004	6,748,564	Scan Stream Sequencing for Testing Integrated Circuits	Granted	P0321
United States	12/21/2000	09/746,618	---	---	Optical Coupling for Testing Integrated Circuits	Pending	P0329
United States	02/10/2001	09/781,488	02/11/2003	6,518,571	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246

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United States	05/31/2001	09/871,541	02/04/2003	6,514,866	Chemical Enhanced Focused Ion Beam Micro-Machining of Copper	Granted	P0345
United States	08/07/2001	09/924,736	01/06/2004	6,672,947	Method for Global Die Thinning and Polishing of Flip-Chip Packaged Integrated Circuits	Granted	P0338
United States	10/18/2001	10/004,018	05/18/2004	6,737,853	Photoconductive-Sampling Voltage Measurement	Granted	P0272
United States	01/23/2002	10/056,287	---	---	Circuit and Method for Distributing Events in an Event Stream	Pending	P0363
United States	01/24/2002	10/057,134	---	---	Comparator Circuit for Differential Swing Comparison and Common-Mode Voltage Comparison	Pending	P0364
United States	01/30/2002	10/066,123	---	---	PICA System Timing Measurement & Calibration	Pending	P0372
United States	02/19/2002	10/079,780	---	---	PICA System Detector Calibration	Pending	P0373
United States	03/18/2002	10/101,564	---	---	Test System Formatters	Pending	P0348

**U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CRENDENCE SYSTEMS CORPORATION**

<u>Country</u>	<u>Application Date</u>	<u>Application No.</u>	<u>Grant Date</u>	<u>Patent No.</u>	<u>Title</u>	<u>Status</u>	<u>Docket</u>
United States	03/19/2002	10/102,526	---	---	Test System Algorithmic Program Generators	Pending	P0350
United States	03/25/2002	10/106,280	---	---	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	Pending	P0352
United States	04/24/2002	10/132,051	02/18/2003	6,522,162	Test System Having Interface Module	Granted	P0339
United States	04/30/2002	10/136,710	---	---	Open-Loop for Waveform Acquisition	Pending	P0355
United States	05/30/2002	10/159,527	---	---	Sub-Resolution Alignment of Images	Pending	P0356
United States	05/30/2002	10/161,272	---	---	Method and Apparatus for Determining Thickness of a Semiconductor Substrate at the Floor	Pending	P0365
United States	05/30/2002	10/160,606	---	---	Method and Apparatus for Forming a Trench Through a Semiconductor Substrate	Pending	P0369
United States	07/16/2002	10/197,134	06/01/2004	6,744,267	Test System and Methodology	Granted	P0370

**REDACTED**

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	11/06/2002	10/288,896	---	---	Precise, In-situ Endpoint Detection for Charged Particle Beam	Pending	P0311

REDACTED

United States	02/18/2003	10/371,353	---	---	Signal Paths Providing Multiple Test Configurations	Pending	P0374
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United States	03/04/2003	10/382,343	---	---	Method and Apparatus for Accessing Internal Nodes of an Integrated Circuit Using IC Package Substrate	Pending	P0318
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United States	04/21/2003	10/420,675	---	---	Method for Surface Preparation to Enable Uniform Etching of Polycrystalline Materials	Pending	P0382
United States	04/23/2003	10/421,059	---	---	Method for Backside Die Thinning and Polishing of Packaged Integrated Circuits	Pending	P0338

REDACTED

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	10/03/2003	10/678,438	---	---	FIB Milling of Copper over Organic Dielectrics	Pending	P0395
REDACTED							
United States	12/08/2003	10/466,366	---	---	Power Supply Device for a Component Testing Installation	Pending	P0353
REDACTED							

**UNITED STATES PATENT AND TRADEMARK OFFICE**UNDER SECRETARY OF COMMERCE FOR INTELLECTUAL PROPERTY AND  
DIRECTOR OF THE UNITED STATES PATENT AND TRADEMARK OFFICE

JANUARY 21, 2004

PTAS

SKADDEN, ARPS, SLATE, MEAGHER  
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UNITED STATES PATENT AND TRADEMARK OFFICE  
NOTICE OF RECORDATION OF ASSIGNMENT DOCUMENT

THE ENCLOSED DOCUMENT HAS BEEN RECORDED BY THE ASSIGNMENT DIVISION OF THE U.S. PATENT AND TRADEMARK OFFICE. A COMPLETE MICROFILM COPY IS AVAILABLE AT THE ASSIGNMENT SEARCH ROOM ON THE REEL AND FRAME NUMBER REFERENCED BELOW.

PLEASE REVIEW ALL INFORMATION CONTAINED ON THIS NOTICE. THE INFORMATION CONTAINED ON THIS RECORDATION NOTICE REFLECTS THE DATA PRESENT IN THE PATENT AND TRADEMARK ASSIGNMENT SYSTEM. IF YOU SHOULD FIND ANY ERRORS OR HAVE QUESTIONS CONCERNING THIS NOTICE, YOU MAY CONTACT THE EMPLOYEE WHOSE NAME APPEARS ON THIS NOTICE AT 703-308-9723. PLEASE SEND REQUEST FOR CORRECTION TO: U.S. PATENT AND TRADEMARK OFFICE, ASSIGNMENT DIVISION, BOX ASSIGNMENTS, CG-4, 1213 JEFFERSON DAVIS HWY, SUITE 320, WASHINGTON, D.C. 20231.

RECORDATION DATE: 06/23/2003

REEL/FRAME: 014268/0115  
NUMBER OF PAGES: 28

BRIEF: ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS).

## ASSIGNOR:

SCHLUMBERGER TECHNOLOGIES, INC.

DOC DATE: 05/10/2002

## ASSIGNEE:

NPTEST, LLC  
150 BAYTECH DRIVE  
SAN JOSE, CALIFORNIA 95134SERIAL NUMBER: 09350611  
PATENT NUMBER:FILING DATE: 07/09/1999  
ISSUE DATE:SERIAL NUMBER: 09410569  
PATENT NUMBER:FILING DATE: 10/01/1999  
ISSUE DATE:SERIAL NUMBER: 09419317  
PATENT NUMBER: 6661836FILING DATE: 10/17/1999  
ISSUE DATE: 12/09/2003

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SERIAL NUMBER: 09421784	FILING DATE: 10/19/1999
PATENT NUMBER: 6671845	ISSUE DATE: 12/30/2003
SERIAL NUMBER: 09628116	FILING DATE: 07/28/2000
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 09648716	FILING DATE: 08/25/2000
PATENT NUMBER: 6622107	ISSUE DATE: 09/16/2003
SERIAL NUMBER: 09676292	FILING DATE: 09/28/2000
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 09675981	FILING DATE: 09/29/2000
PATENT NUMBER: 6630667	ISSUE DATE: 10/07/2003
SERIAL NUMBER: 09679042	FILING DATE: 10/02/2000
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 09696102	FILING DATE: 10/24/2000
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 09746618	FILING DATE: 12/21/2000
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 09924736	FILING DATE: 08/07/2001
PATENT NUMBER: 6672947	ISSUE DATE: 01/06/2004
SERIAL NUMBER: 10004018	FILING DATE: 10/18/2001
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 10056287	FILING DATE: 01/23/2002
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 10057134	FILING DATE: 01/24/2002
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 10066123	FILING DATE: 01/30/2002
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 10079780	FILING DATE: 02/19/2002
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 10101564	FILING DATE: 03/18/2002
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 10102526	FILING DATE: 03/19/2002
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 10106280	FILING DATE: 03/25/2002
PATENT NUMBER:	ISSUE DATE:
SERIAL NUMBER: 10123842	FILING DATE: 04/15/2002
PATENT NUMBER:	ISSUE DATE:



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SERIAL NUMBER: 10421059  
PATENT NUMBER:FILING DATE: 04/23/2003  
ISSUE DATE:SERIAL NUMBER: 10136710  
PATENT NUMBER:FILING DATE: 04/30/2002  
ISSUE DATE:SERIAL NUMBER: 06472427  
PATENT NUMBER: 4594544FILING DATE: 03/07/1983  
ISSUE DATE: 06/10/1986SERIAL NUMBER: 06611454  
PATENT NUMBER: 4623802FILING DATE: 05/17/1984  
ISSUE DATE: 11/18/1986SERIAL NUMBER: 06611266  
PATENT NUMBER: 4651038FILING DATE: 05/17/1984  
ISSUE DATE: 03/17/1987SERIAL NUMBER: 06631958  
PATENT NUMBER: 4673917FILING DATE: 07/18/1984  
ISSUE DATE: 06/16/1987SERIAL NUMBER: 06798592  
PATENT NUMBER: 4706019FILING DATE: 11/15/1985  
ISSUE DATE: 11/10/1987SERIAL NUMBER: 06828157  
PATENT NUMBER: 4721909FILING DATE: 02/10/1986  
ISSUE DATE: 01/26/1988SERIAL NUMBER: 06932762  
PATENT NUMBER: 4795984FILING DATE: 11/19/1986  
ISSUE DATE: 01/03/1989SERIAL NUMBER: 06766905  
PATENT NUMBER: 4864228FILING DATE: 08/16/1985  
ISSUE DATE: 09/05/1989SERIAL NUMBER: 07284775  
PATENT NUMBER: 4910698FILING DATE: 12/12/1988  
ISSUE DATE: 03/20/1990SERIAL NUMBER: 07196776  
PATENT NUMBER: 4912405FILING DATE: 05/17/1988  
ISSUE DATE: 03/27/1990SERIAL NUMBER: 07276359  
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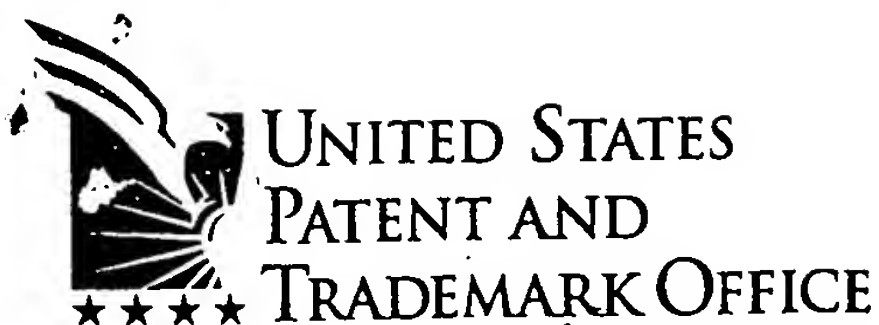
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TODD M. BRIGGS  
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SUITE 2800  
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ASSIGNOR:  
WEST, BURNELL G.

DOC DATE: 01/21/2002

ASSIGNEE:  
SCHLUMBERGER TECHNOLOGIES, INC.  
150 BAYTECH DRIVE  
SAN JOSE, CALIFORNIA 95134-2302

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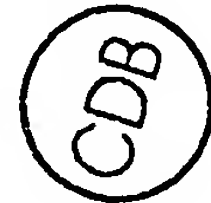
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1. Name of conveying party(ies):

(a) Burnell G. West

Additional name(s) of conveying party(ies) attached?

☐ Yes☒ No

2. Name and address of receiving party(ies):

Name: SCHLUMBERGER TECHNOLOGIES, INC.

Street Address: 150 Baytech Drive

City: San Jose

California 95134-2302

Country: United States

3. Nature of Conveyance:

☒ Assignment☐ Merger☐ Security Agreement☐ Change of Name☐ Other

Execution Date: January 21, 2002

Additional name(s) &amp; address(es) attached?

☐ Yes☒ No

4. Application number(s) or patent number(s):

If this document is being filed together with a new application, the execution date of the application is: January 21, 2002

A. Patent Application No.(s) -

Title: CIRCUIT AND METHOD FOR DISTRIBUTING  
EVENTS IN AN EVENT STREAM

B. Patent No.(s)

10/056287

Additional numbers attached?



Yes



No

5. Name and address of party to whom correspondence concerning document should be mailed:

Name: Todd M. Briggs

Internal Address: SKJERVEN MORRILL MacPHERSON LLP

Street Address: 3 EMBARCADERO CENTER, SUITE 2800

City SAN FRANCISCO State CA Zip 94111

6. Total number of applications and patents involved: One

7. Total fee (37 CFR 3.41): \$40.00



Authorized to be charged to Deposit Account 19-2386



Charge Deposit Account 19-2386 for any additional fees required for this conveyance and credit deposit account 19-2386 any amounts overpaid

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8. Statement and signature.

To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.

Todd M. Briggs

44,040

Name of Person Signing

Signature

Date

1-23-02

Total number of pages including cover sheet, attachments, and documents: Two



# ASSIGNMENT

For good and valuable consideration, receipt of which is hereby acknowledged, I, Burnell G. West of Fremont, California, hereby sell, assign and transfer to **SCHLUMBERGER TECHNOLOGIES, INC.**, a Delaware corporation, having a place of business at 150 Baytech Drive, San Jose, California 95134-2302, its successors and assigns, the entire right, title and interest throughout the world in my invention in

## **CIRCUIT AND METHOD FOR DISTRIBUTING EVENTS IN AN EVENT STREAM**

for which I have executed a United States patent application on or about the date of this assignment, and all patent applications and patents of every country for said invention, including divisions, reissues, continuations and extensions thereof, and all rights of priority resulting from the filing of said applications; I authorize the above-named assignee to apply for patents of foreign countries for said invention, and to claim all rights of priority without further authorization from me; I agree to execute all papers useful in connection with said United States and foreign applications, and generally to do everything possible to aid said assignee, its successors, assigns and nominees, at their request and expense, in obtaining and enforcing patents for said invention in all countries; and I request the Commissioner of Patents and Trademarks to issue all patents granted for said invention to the above-named assignee, its successors and assigns.

Executed this 21 day of January, 2002.

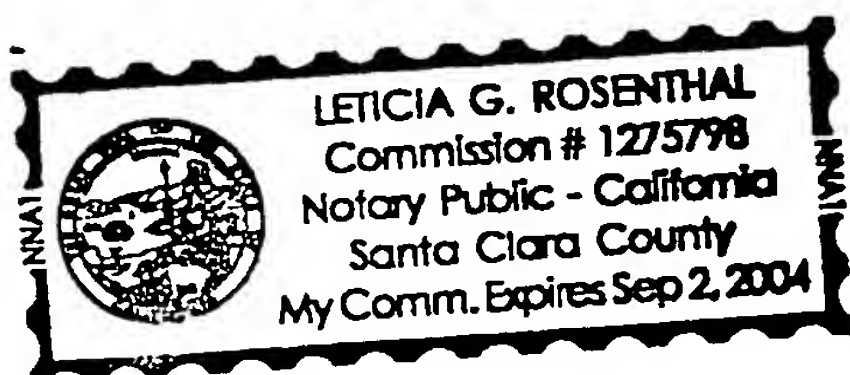
Burnell G. West  
Burnell G. West

State of California )  
County of Santa Clara ) ss

On January 21, 2002 before me, Leticia G. Rosenthal, Notary Public, personally appeared Burnell G. West personally known to me or proved to me on the basis of satisfactory evidence to be the person(s) whose name(s) is(~~are~~) subscribed to the within instrument and acknowledged to me that he/~~she~~/they executed the same in his/~~her~~/their authorized capacity(~~ies~~), and that by his/~~her~~/their signature(s) on the instrument the person(s), or the entity upon behalf of which the person(s) acted, executed the instrument.

WITNESS my hand and official seal.

Leticia G. Rosenthal  
SIGNATURE OF NOTARY



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